

### Part I: Ad-Hoc Approaches for Variability

1. Introduction
2. Runtime Variability and Design Patterns
3. Compile-Time Variability with Clone-and-Own

### Part II: Modeling & Implementing Features

4. Feature Modeling
5. Conditional Compilation
6. Modular Features
7. Languages for Features
8. Development Process

### Part III: Quality Assurance and Outlook

9. Feature Interactions
10. Product-Line Analyses
11. **Product-Line Testing**
12. Evolution and Maintenance

#### 11a. Challenges of Product-Line Testing

Recap: Software Testing  
Test-Case Design in Single-System Engineering  
Testing All Configurations  
Testing One Configuration  
Sample-Based Testing  
Summary

#### 11b. Combinatorial Interaction Testing

Pairwise Interaction Testing  
T-Wise Interaction Testing  
Algorithms for Combinatorial Interaction Testing  
Efficiency of Combinatorial Interaction Testing  
Effectiveness of Combinatorial Interaction Testing  
Summary

#### 11c. Solution-Space Sampling

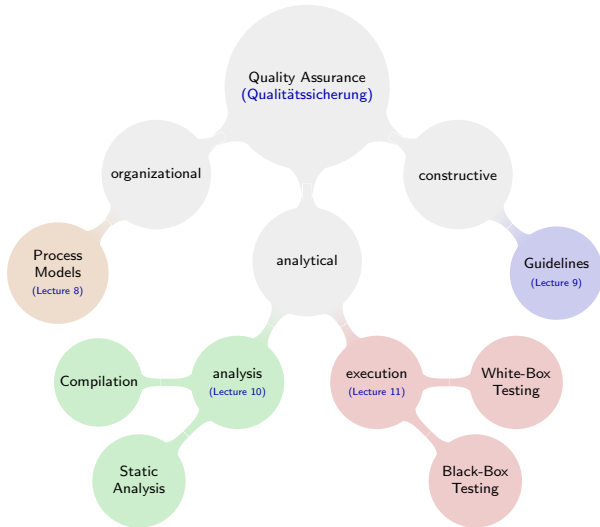
Coverage in Single-System Engineering  
Coverage of Ifdef Blocks  
Presence-Condition Coverage  
Overview on Coverage Criteria  
Input for Sampling Algorithms  
Summary  
FAQ

## 11. Product-Line Testing – Handout

Software Product Lines | Thomas Thüm, Sebastian Krieter, Timo Kehrer, Elias Kuiter | June 21, 2023

# Recap: Quality Assurance

[Ludewig and Lichter 2013]



## Lectures on Quality Assurance

how to **avoid** variability bugs  
(esp. feature interactions) ...

- with processes [Lecture 8]  
(e.g., domain scoping)
- with guidelines [Lecture 9]

how to **find** variability bugs ...

- **statically** [Lecture 10]
- **dynamically** [Lecture 11]
  - challenges of product-line testing in Part a
  - black-box testing in Part b
  - white-box testing in Part c

# 11. Product-Line Testing

## 11a. Challenges of Product-Line Testing

Recap: Software Testing

Test-Case Design in Single-System Engineering

Testing All Configurations

Testing One Configuration

Sample-Based Testing

Summary

## 11b. Combinatorial Interaction Testing

## 11c. Solution-Space Sampling

# Recap: Software Testing

## Software Testing

[Sommerville]

“Testing is intended to show that a program does what it is intended to do and to discover program defects before it is put into use.”

## Validation Testing

[Sommerville]

“Demonstrate to the developer and the customer that the software meets its requirements.”

## Defect Testing

[Sommerville]

“Find inputs or input sequences where the behavior of the software is incorrect, undesirable, or does not conform to its specification.”

## Stages of Testing

[Sommerville]

1. “**Development testing**, where the system is tested during development to discover bugs and defects”
2. “**Release testing**, where a separate testing team tests a complete version of the system before it is released to users”
3. “**User testing**, where users or potential users of a system test the system in their own environment”

## Manual vs Automated Testing

[Sommerville]

“In **manual testing**, a tester runs the program with some test data and compares the results to their expectations. [...] In **automated testing**, the tests are encoded in a program that is run each time the system under development is to be tested.”

# Recap: Test-Case Design

## Systematic Test

[Ludewig and Lichter 2013]

A systematic test is a test, in which

1. the **setup** is defined,
2. the **inputs** are chosen systematically,
3. the **results** are documented and evaluated by criteria being defined prior to the test.

## Test Case

[Ludewig and Lichter 2013]

In a test, a number of test cases are executed, whereas each test case consists **input values** for a single execution and **expected outputs**. An **exhaustive test** refers a test in which the test cases exercise all the possible inputs.

## Goal

[Ludewig and Lichter 2013]

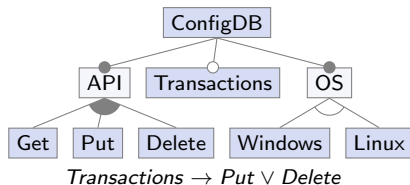
Detect a large number of failures with a low number of test cases. A test case (execution) is **positive**, if it detects a failure, and **successful** if it detects an unknown failure.

## An ideal test case is ...

[Ludewig and Lichter 2013]

- representative: represents a large number of feasible test cases
- failure sensitive: has a high probability to detect a failure
- non-redundant: does not check what other test cases already check

# Testing All Configurations



## Recap: 26 Valid Configurations

[Lecture 4]

{C, G, W}	{C, G, L}
{C, P, W}	{C, P, L}
{C, G, P, W}	{C, G, P, L}
{C, D, W}	{C, D, L}
{C, G, D, W}	{C, G, D, L}
{C, P, D, W}	{C, P, D, L}
{C, G, P, D, W}	{C, G, P, D, L}
{C, P, T, W}	{C, P, T, L}
{C, G, P, T, W}	{C, G, P, T, L}
{C, D, T, W}	{C, D, T, L}
{C, G, D, T, W}	{C, G, D, T, L}
{C, P, D, T, W}	{C, P, D, T, L}
{C, G, P, D, T, W}	{C, G, P, D, T, L}

## Discussion

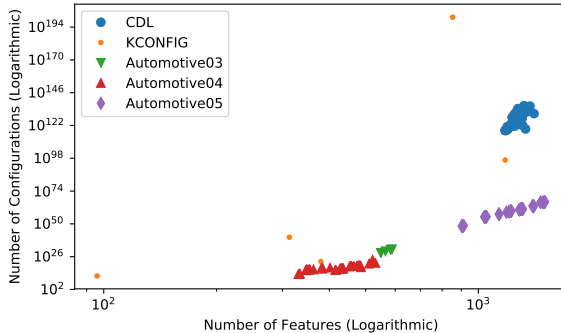
- only feasible for **small** product lines (few valid configurations)
- redundant test effort
- large product lines: not feasible to generate and compile all configurations
  - (some) large product lines: even number of valid configurations is unknown



# Testing All Configurations

## Recap: Industrial Configuration Spaces

[Lecture 1]



Why being complete on the configurations then?



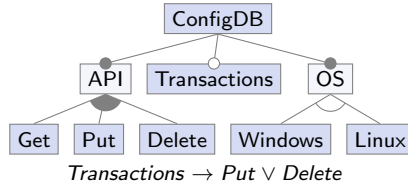
Edsger W. Dijkstra (1972)

“Program testing can be a very effective way to show the presence of bugs, but it is hopelessly inadequate for showing their absence.”

[The Humble Programmer]



# Testing One Configuration



## Recap: 26 Valid Configurations

[Lecture 4]

{C, G, W}	{C, G, L}
{C, P, W}	{C, P, L}
{C, G, P, W}	{C, G, P, L}
{C, D, W}	{C, D, L}
{C, G, D, W}	{C, G, D, L}
{C, P, D, W}	{C, P, D, L}
{C, G, P, D, W}	{C, G, P, D, L}
{C, P, T, W}	{C, P, T, L}
{C, G, P, T, W}	{C, G, P, T, L}
{C, D, T, W}	{C, D, T, L}
{C, G, D, T, W}	{C, G, D, T, L}
{C, P, D, T, W}	{C, P, D, T, L}
{C, G, P, D, T, W}	{C, G, P, D, T, L}

## Discussion

- applicable to large product lines
- strategy in practice: all-yes-config (configuration with many features selected)
- no redundant test effort (from configurations)
- often unfeasible to test all features with a single configuration (e.g., Windows and Linux)

$\Rightarrow$  unnoticed feature interactions

[Lecture 9]

## What about interactions with missing features?



# Sample-Based Testing

## Intuition

- to analyze the product line, just analyze **some products**
- sample refers to a subset of all valid configurations
- common technique to test a product line
- sample configurations chosen by experts, randomly, or systematically

## Advantages and Challenges

- + lower effort than testing all configurations
- + higher chance to detect defects than testing one configuration
- how many configurations to test?  
which configurations to test?



# Challenges of Product-Line Testing – Summary

## Lessons Learned

- recap on software testing and test-case design
- testing all configurations
- testing one configuration
- sample-based testing

## Further Reading

- Varshosaz et al. 2018: overview on sampling literature
- Sampling Database: database on sampling algorithms and evaluations

## Practice

Recap on feature interactions: What are examples of interactions that cannot be detected statically (cf. Lecture 10) and could be missed when testing a single configuration only?

# 11. Product-Line Testing

## 11a. Challenges of Product-Line Testing

## 11b. Combinatorial Interaction Testing

- Pairwise Interaction Testing

- T-Wise Interaction Testing

- Algorithms for Combinatorial Interaction Testing

- Efficiency of Combinatorial Interaction Testing

- Effectiveness of Combinatorial Interaction Testing

- Summary

## 11c. Solution-Space Sampling

# Recap: Black-Box Testing

## Motivation

[Ludewig and Lichter 2013]

- source code not always available (e.g., outsourced components, obfuscated code)
- errors are not equally distributed

## Black-Box Testing

[Ludewig and Lichter 2013]

- test-case design based on specification
- source code and its inner structure is ignored (assumed as a black-box)

## Sample Configuration $\neq$ Test Case

- test case: concrete inputs and expected outputs for a program
  - sample configuration: selection of features to derive the program
  - both needed when testing product lines
  - often confused in the literature
  - test case derivation
    - out of scope here
    - global tests (i.e., identical for all configurations)
    - product-line implementation technique used to automatically derive configuration-specific tests
- [Lecture 8]
- on next slides: idea of black-box testing applied to derive sample configuration

# Pairwise Interaction Testing

## Configurations with the Interaction Get $\wedge$ Put

{C, G, W}	{C, G, L}
{C, P, W}	{C, P, L}
{C, G, P, W}	{C, G, P, L}
{C, D, W}	{C, D, L}
{C, G, D, W}	{C, G, D, L}
{C, P, D, W}	{C, P, D, L}
{C, G, P, D, W}	{C, G, P, D, L}
{C, P, T, W}	{C, P, T, L}
{C, G, P, T, W}	{C, G, P, T, L}
{C, D, T, W}	{C, D, T, L}
{C, G, D, T, W}	{C, G, D, T, L}
{C, P, D, T, W}	{C, P, D, T, L}
{C, G, P, D, T, W}	{C, G, P, D, T, L}

## Pairwise Interaction Testing

- create a sample  $S \subseteq C$ , in which every pairwise interaction is covered by at least one configuration
- test every configuration in  $S$

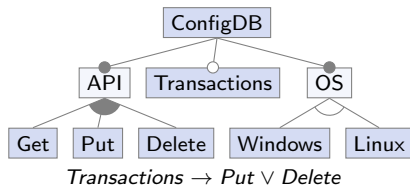
## Discussion

- applicable to large product lines
- reduced redundant effort compared to testing all configurations
- full coverage guarantee (opposed to random configurations)
- still requires good test cases (program inputs)
- hard to compute small sample sets

## Pairwise Combinations

- four combinations between  $A$  and  $B$ 
  - both selected:  $A \wedge B$
  - one selected:  $\neg A \wedge B$  and  $A \wedge \neg B$
  - none selected:  $\neg A \wedge \neg B$

# Pairwise Coverage



## Interactions to Cover

- exclude abstract features (e.g., *API*, *OS*)
- exclude features contained in every configuration (e.g., *C*)
- exclude invalid combinations (e.g.,  $W \wedge L$ )

## Pairwise Interactions

$G \wedge P$	$\neg G \wedge P$	$G \wedge \neg P$	$\neg G \wedge \neg P$
$G \wedge D$	$\neg G \wedge D$	$G \wedge \neg D$	$\neg G \wedge \neg D$
$G \wedge T$	$\neg G \wedge T$	$G \wedge \neg T$	$\neg G \wedge \neg T$
$G \wedge W$	$\neg G \wedge W$	$G \wedge \neg W$	$\neg G \wedge \neg W$
$G \wedge L$	$\neg G \wedge L$	$G \wedge \neg L$	$\neg G \wedge \neg L$
$P \wedge D$	$\neg P \wedge D$	$P \wedge \neg D$	$\neg P \wedge \neg D$
$P \wedge T$	$\neg P \wedge T$	$P \wedge \neg T$	$\neg P \wedge \neg T$
$P \wedge W$	$\neg P \wedge W$	$P \wedge \neg W$	$\neg P \wedge \neg W$
$P \wedge L$	$\neg P \wedge L$	$P \wedge \neg L$	$\neg P \wedge \neg L$
$D \wedge T$	$\neg D \wedge T$	$D \wedge \neg T$	$\neg D \wedge \neg T$
$D \wedge W$	$\neg D \wedge W$	$D \wedge \neg W$	$\neg D \wedge \neg W$
$D \wedge L$	$\neg D \wedge L$	$D \wedge \neg L$	$\neg D \wedge \neg L$
$T \wedge W$	$\neg T \wedge W$	$T \wedge \neg W$	$\neg T \wedge \neg W$
$T \wedge L$	$\neg T \wedge L$	$T \wedge \neg L$	$\neg T \wedge \neg L$
	$W \wedge \neg L$	$\neg W \wedge L$	

## Pairwise Coverage with Six Configurations

$\{C, P, D, T, W\}$   
 $\{C, G, D, L\}$   
 $\{C, G, P, T, L\}$   
 $\{C, G, W\}$   
 $\{C, P, W\}$   
 $\{C, D, T, L\}$

# T-Wise Interaction Testing

## T-Wise Interaction Testing

- generalization of pairwise interaction testing
- t-wise coverage: every t-wise interaction is covered by at least one configuration in the sample
- $t = 1$ : every feature is selected and also deselected
- $t = 2$ : pairwise interaction coverage
- $t = 3$ : every valid combination of three features covered

## $t = 3$ Interactions

for the features  $G$ ,  $P$ , and  $D$ :

$G \wedge P \wedge D$	$\neg G \wedge P \wedge D$
$G \wedge P \wedge \neg D$	$\neg G \wedge P \wedge \neg D$
$G \wedge \neg P \wedge D$	$\neg G \wedge \neg P \wedge D$
$G \wedge \neg P \wedge \neg D$	$\neg G \wedge \neg P \wedge \neg D$



# Algorithms for Combinatorial Interaction Testing

## A Greedy Algorithm

idea: select configuration that cover most missing interactions in each step

1. randomly choose first configuration
2. find next optimal configuration
3. repeat step 2 until all interactions are covered

## Challenges and Optimizations

- non-deterministic: different sample for each run (cf. Step 1)
  - starting with all-yes-config?  $\Rightarrow$  covers more code
- iterating all valid configurations does not scale (cf. Step 2)
- greedy strategy: optimal configuration in each step does not guarantee optimal sample

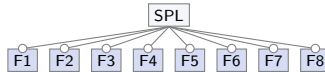
## ICPL

[Johansen et al. 2012]

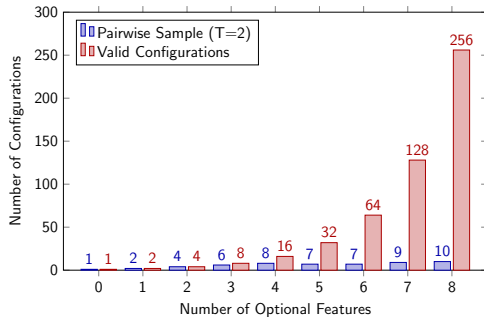
- widespread greedy algorithm
- iterates over all interactions
  - identifies core and dead features early
  - identifies invalid and already covered interactions
  - utilizes parallelization
- incrementally increases  $t$  up to desired value
- performance shown on next slides

# Efficiency of Combinatorial Interaction Testing [Johansen et al. 2012]

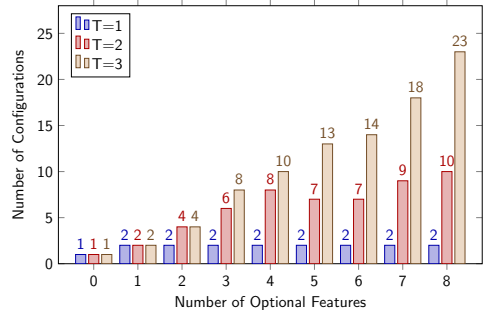
**Assumption: All Features are Optional**



**Number of Configurations in Pairwise Sample**

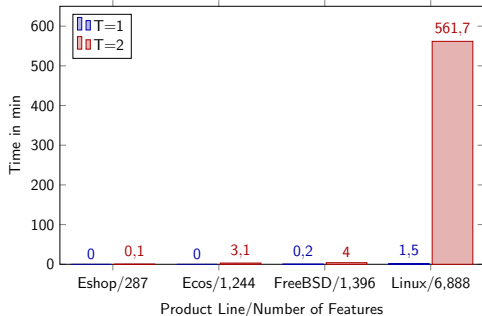


**Number of Configurations in T-Wise Sample**



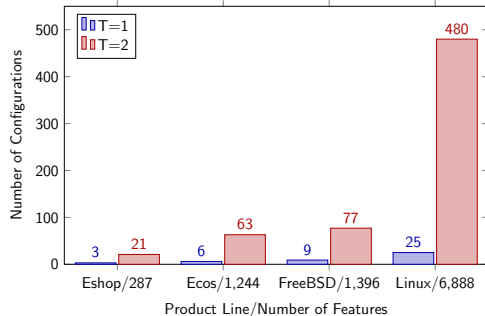
# Efficiency of Combinatorial Interaction Testing [Johansen et al. 2012]

Time in Minutes to Compute Sample



- about 9h for Linux
- 480 configuration in pairwise sample

Number of Configurations in Sample

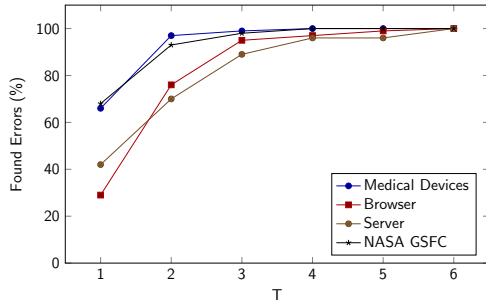


- Linux kernel v2.6.28.6 (February 2009)
- 6,888 features
- 187,193 clauses in conjunctive normal form

# Effectiveness of Combinatorial Interaction Testing

## Effectiveness of Interaction Testing

[Kuhn et al. 2004]



### Trade-Off

large t: high coverage (more effective)

small t: low testing effort (more efficient)

# Combinatorial Interaction Testing – Summary

## Lessons Learned

- recap on black-box testing
- combinatorial interaction testing: pairwise testing, t-wise testing
- efficiency: number of configurations, time to compute sample
- effectiveness: percentage of found defects

## Further Reading

- Johansen et al. 2012 – popular t-wise sampling algorithm ICPL
- Krieter et al. 2020 – alternative t-wise sampling algorithm YASA

## Practice

Why is it hard to find a good trade-off between efficiency and effectiveness?

# 11. Product-Line Testing

## 11a. Challenges of Product-Line Testing

## 11b. Combinatorial Interaction Testing

## 11c. Solution-Space Sampling

- Coverage in Single-System Engineering

- Coverage of Ifdef Blocks

- Presence-Condition Coverage

- Overview on Coverage Criteria

- Input for Sampling Algorithms

- Summary

- FAQ

# Recap: Coverage in White-Box Testing [Ludewig and Lichter 2013]

## White-Box Testing

- inner structure of test object is used
- idea: coverage of structural elements
  - code translated into control flow graph
  - specific test case (concrete inputs)  
derived from logical test case (conditions)  
derived from path in control flow graph

## Coverage Criteria

1. **statement coverage** :  
all statements are executed for at least one test case
2. **branching coverage** : statement coverage and all branches of branching statement are executed
3. **term coverage** :  
branching coverage and all terms used in a branching statement ( $n$ ) are combined exhaustively ( $2^n$ ) (simplified)

## Can You Spot Problems in the Elevator Product Line?

[Varshosaz et al. 2018]

```
1 class ControlUnit {
2     Elevator elevator;
3     ElevatorState state, nextState;
4     ///if FIFO
5     Req req = new Req();
6     ///elif DirectedCall
7     Req req = new UndReq(this);
8     Req dreq = new DirReq(null);
9     ///else
0     Req req = new Req(this);
1     ///endif
2     void run() {
3         while (true) {
4             calculateNextState();
5             setDirection(nextState);
6
7             ///if DirectedCall
8             sortQueue();
9             ///endif
10        }
11    }
12    void calculateNextState() {
13        ///if Sabbath
14        if (sabbathNextState()) return;
15        ///endif
16        ///if Service
17        if (serviceNextState()) return;
18        ///endif
19        ///if FIFO
20        callButtonsNextState(dreq);
21        ///endif
22    }
23    boolean serviceNextState() {...}
24    ///endif
25    boolean sabbathNextState() {...}
26    ///endif
27    ///if DirectedCall
28    void callButtonsNextState(Req d) {...}
29    ///endif
30    void sortQueue() {...}
31    ///endif
32 }
```

- Line 29: compiler error (i.e., field `dreq` undefined) when  $FIFO \wedge \neg DirectedCall$
- Line 8: null pointer exception when  $DirectedCall \wedge \neg FIFO$
- both problems detectable with pairwise coverage, but presence conditions are more complicated in practice
- also: pairwise coverage often too much effort for large configuration spaces / continuous integration

### Coverage of Ifdef Blocks

[Tartler et al. 2012]

- every block selected for at least one configuration in the sample (cf. statement coverage)



# Presence-Condition Coverage

## Presence-Condition Coverage

[Krieter et al. 2022]

- application of t-wise interaction testing to presence conditions
- recap presence condition: formula specifying exactly those configurations under which a block is present
- t-wise presence condition coverage: every t-wise interaction of presence conditions is covered by at least one configuration in the sample
- $t = 1$ : every block is selected and also deselected (i.e., more than Tartler's coverage of ifdef blocks)
- $t = 2$ : every combination of two blocks covered
- $t = 3$ : every combination of three blocks covered

## $T=3$ Presence-Condition Interactions

for the blocks  $a$ ,  $b$ , and  $c$  with presence conditions  $A$ ,  $B$ , and  $C$ :

$A \wedge B \wedge C$	$\neg A \wedge B \wedge C$
$A \wedge B \wedge \neg C$	$\neg A \wedge B \wedge \neg C$
$A \wedge \neg B \wedge C$	$\neg A \wedge \neg B \wedge C$
$A \wedge \neg B \wedge \neg C$	$\neg A \wedge \neg B \wedge \neg C$

## Presence-Condition Coverage

[Krieter et al. 2022]

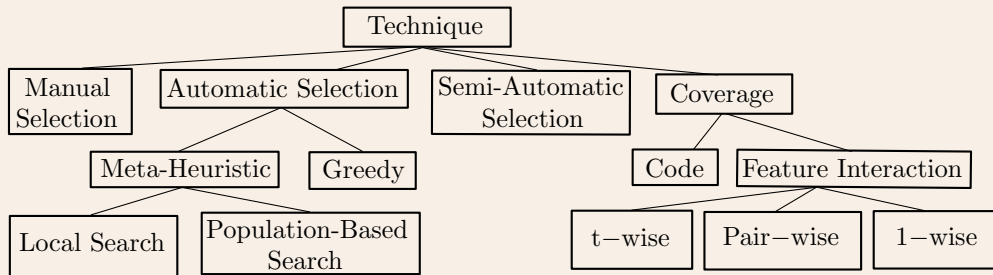
- coverage of solution space (not problem space)
- aka. solution-space sampling
- for same  $t$ : often fewer configurations and similar effectiveness than feature interaction coverage
- also feasible by translating presence conditions into feature model

[Hentze et al. 2022]

# Overview on Coverage Criteria

## Techniques & Coverage Criteria

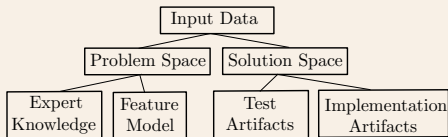
[Varshosaz et al. 2018]



# Input for Sampling Algorithms

## Input Data

[Varshosaz et al. 2018]



## Further Domain Knowledge

[Varshosaz et al. 2018]

- in addition to feature model
- e.g., configurations chosen by experts
- e.g., specialized feature model for sampling

## Part 2: Combinatorial Interaction Testing

- (Problem-Space Sampling)
- **feature model** used to consider only valid configurations

## Part 3: Solution-Space Sampling

- mapping from features to **implementation artifacts**
- **feature model** used to consider only valid configurations

## Combinatorial Reduction of Tests

[Kim et al. 2011]

- which configurations matter for each test?
- analyze **unit tests** and **impl. artifacts**
- **feature model** used to consider only valid configurations

# Solution-Space Sampling – Summary

## Lessons Learned

- recap on white-box testing and coverage criteria
- coverage of ifdef blocks
- t-wise presence condition coverage
- overview on techniques, coverage criteria, input data for sampling

## Further Reading

- Tartler et al. 2012: covering every ifdef block (but not their absence)
- Krieter et al. 2022: solution-space sampling as discussed in this part
- Hentze et al. 2022: translation of presence conditions into feature model + reuse of problem-space sampling

## Practice

Does the order of configurations matter during testing?

[Al-Hajjaji et al. 2019]

# FAQ – 11. Product-Line Testing

## Lecture 11a

- What is the goal of quality assurance for software product lines?
- How can product lines be tested?
- Why is testing product lines challenging?
- What are (dis-)advantages of testing all configurations?
- What are (dis-)advantages of testing only one configuration?
- What is sample-based testing?
- What is a sample?
- How can a sample be computed?

## Lecture 11b

- How is black-box testing used for testing product lines?
- What is the difference between a test configuration and a test case?
- What are (dis-)advantages of combinatorial interaction testing?
- What is pairwise interaction testing?
- What is t-wise interaction testing?
- When does a sample achieve 100% pairwise coverage?
- How can a t-wise sample be computed?

## Lecture 11c

- How can white-box testing be used for testing product lines?
- What are potential problems with t-wise interaction testing?
- What is presence condition coverage?
- What are different techniques for t-wise sampling?
- Which additional inputs can be used for sampling algorithms?
- How efficient and how effective are sampling algorithms?